



AF  
zw

Docket No. AMDP458US

E0796

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re **PATENT** application of:

Applicant: Ramkumar Subramanian et al.

Application No.: 09/634,302

For: SYSTEM AND METHOD FOR DEFECT IDENTIFICATION AND  
LOCATION USING AN OPTICAL INDICIA DEVICE

Filing Date: August 8, 2000

Examiner: Richard A. Rosenberger

Art Unit: 2877

REPLY TO OFFICE ACTION DATED FEBRUARY 11, 2005

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

Favorable reconsideration of the above-identified application is respectfully  
requested in view of the following amendments and remarks.